

**Amendments to the Claims:**

1-14. (Cancelled)

15. (Currently Amended) A method for testing memory, said method comprising:

testing performing a first test, wherein functional memory is tested;

repairing the functional memory by adding access to redundant elements, thereby providing repaired functional memory;

re-testing performing a second test, wherein the repaired functional memory which has been repaired is tested;

after repairing the functional memory by adding access to redundant elements and after re-testing testing the repaired functional memory which has been repaired, adding access to additional redundant memory without using the additional redundant memory to replace functional memory, wherein the additional redundant memory is not required for the repair of the functional memory; and

after repairing and re-testing the functional memory and adding access to the additional redundant memory which has been added which was not required for the repair, testing the additional redundant memory which has been added which was not required for the repair performing a third test, wherein the redundant memory is tested.

16. (Currently Amended) A method as recited in claim 15, further comprising using repair information to repair the functional memory.

17. (Currently Amended) A method as recited in claim 15, wherein the step of adding access to ~~additional~~ redundant memory which is not required for the repair comprises forcing usage of redundant elements which are not needed to be used for repairing the functional memory.

18. (Currently Amended) A method as recited in claim 15, wherein the step of adding access to ~~additional~~ redundant memory which is not required for the repair comprises faking defects to remap good elements with redundant elements.

19. (Previously Presented) A method as recited in claim 15, further comprising checking interaction between redundant elements of the memory which are not used and adjacent functional memory.

20. (Currently Amended) A method as recited in claim 15, ~~further comprising forcing usage of all redundant elements, and determining whether a detected failure is associated with~~ redundant elements wherein the step of adding access to redundant memory not required for repair of the functional memory comprises adding access to all remaining redundant memory, and wherein the step of performing a third test comprises testing all the remaining redundant memory.

21. (Currently Amended) A mode for testing memory, said mode comprising:

means for ~~testing~~ performing a first test, wherein functional memory is tested;

repairing the functional memory by adding access to redundant elements thereby  
providing repaired functional memory;

means for performing a second test, wherein re-testing the repaired functional memory  
which has been repaired is tested;

means for, after repairing the functional memory ~~by adding access to redundant elements~~  
and after ~~re-testing~~ testing the repaired functional memory which has been repaired, adding  
access to ~~additional~~ redundant memory ~~without using the additional redundant memory to replace~~  
functional memory, ~~wherein the additional redundant memory is not required for the repair of the~~  
functional memory; and

means for, after repairing and re-testing the functional memory ~~and adding access to~~  
~~the additional redundant memory which has been added which was not required for the repair,~~  
~~testing the additional redundant memory which has been added which was not required for the~~  
~~repair~~ performing a third test, wherein the redundant memory is tested.

22. (Currently Amended) A mode as recited in claim 21, further comprising means for using  
repair information to repair the functional memory.

23. (Currently Amended) A mode as recited in claim 21, further comprising means for forcing usage of redundant elements which are not needed to be used for repairing the functional memory.

24. (Previously Presented) A mode as recited in claim 21, further comprising means for faking defects to remap good elements with redundant elements.

25. (Previously Presented) A mode as recited in claim 21, further comprising means for checking interaction between redundant elements of the memory which are not used and adjacent functional memory.

26. (Currently Amended) A mode as recited in claim 21, ~~further comprising means for forcing usage of all redundant elements, and determining whether a detected failure is associated with redundant elements~~ wherein the means for adding access to redundant memory not required for repair of the functional memory comprises means for adding access to all remaining redundant memory, and wherein the means for performing a third test comprises means for testing all the remaining redundant memory.